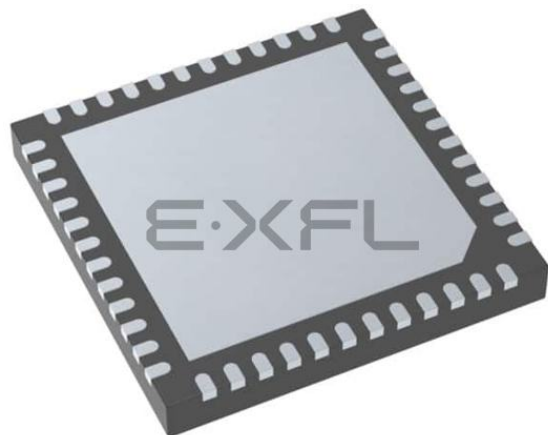




Welcome to [E-XFL.COM](#)

What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	CANbus, EBI/EMI, I ² C, IrDA, LINbus, MMC/SDIO, QSPI, SAI, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	36
Program Memory Size	1MB (1M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	320K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 10x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-UFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f413cgu6

Table 41.	High-speed external user clock characteristics	109
Table 42.	Low-speed external user clock characteristics	109
Table 43.	HSE 4-26 MHz oscillator characteristics	111
Table 44.	LSE oscillator characteristics ($f_{LSE} = 32.768$ kHz)	112
Table 45.	HSI oscillator characteristics	113
Table 46.	LSI oscillator characteristics	114
Table 47.	Main PLL characteristics	115
Table 48.	PLLI2S (audio PLL) characteristics	116
Table 49.	SSCG parameter constraints	117
Table 50.	Flash memory characteristics	118
Table 51.	Flash memory programming	119
Table 52.	Flash memory programming with V_{PP} voltage	120
Table 53.	Flash memory endurance and data retention	120
Table 54.	EMS characteristics for LQFP144 package	121
Table 55.	EMI characteristics for LQFP144	122
Table 56.	ESD absolute maximum ratings	123
Table 57.	Electrical sensitivities	123
Table 58.	I/O current injection susceptibility	124
Table 59.	I/O static characteristics	124
Table 60.	Output voltage characteristics	127
Table 61.	I/O AC characteristics	128
Table 62.	NRST pin characteristics	129
Table 63.	TIMx characteristics	130
Table 64.	I ² C characteristics	131
Table 65.	SCL frequency ($f_{PCLK1} = 50$ MHz, $V_{DD} = V_{DD_I2C} = 3.3$ V)	132
Table 66.	FMPI ² C characteristics	133
Table 67.	SPI dynamic characteristics	135
Table 68.	I ² S dynamic characteristics	138
Table 69.	SAI characteristics	140
Table 70.	QSPI dynamic characteristics in SDR mode	142
Table 71.	QSPI dynamic characteristics in DDR mode	142
Table 72.	USB OTG FS startup time	143
Table 73.	USB OTG FS DC electrical characteristics	143
Table 74.	USB OTG FS electrical characteristics	144
Table 75.	ADC characteristics	145
Table 76.	ADC accuracy at $f_{ADC} = 18$ MHz	146
Table 77.	ADC accuracy at $f_{ADC} = 30$ MHz	147
Table 78.	ADC accuracy at $f_{ADC} = 36$ MHz	147
Table 79.	ADC dynamic accuracy at $f_{ADC} = 18$ MHz - limited test conditions	147
Table 80.	ADC dynamic accuracy at $f_{ADC} = 36$ MHz - limited test conditions	147
Table 81.	Temperature sensor characteristics	151
Table 82.	Temperature sensor calibration values	151
Table 83.	V_{BAT} monitoring characteristics	152
Table 84.	Embedded internal reference voltage	152
Table 85.	Internal reference voltage calibration values	152
Table 86.	DAC characteristics	153
Table 87.	DFSDM characteristics	156
Table 88.	Asynchronous non-multiplexed SRAM/PSRAM/NOR - read timings	161
Table 89.	Asynchronous non-multiplexed SRAM/PSRAM/NOR read - NWAIT timings	161
Table 90.	Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings	162

3.25 Serial peripheral interface (SPI)

The devices feature five SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1, SPI4 and SPI5 can communicate at up to 50 Mbit/s, SPI2 and SPI3 can communicate at up to 25 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes. All SPIs can be served by the DMA controller.

The SPI interfaces can be configured to operate in TI mode for communications in master mode and slave mode.

3.26 Inter-integrated sound (I²S)

Five standard I²S interfaces (multiplexed with SPI1 to SPI5) are available. They can be operated in master or slave mode, in simplex communication mode, and full duplex mode for I2S2 and I2S3. All I²S interfaces can be configured to operate with a 16-/32-bit resolution as an input or output channel. I2Sx audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I²S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I²Sx interfaces can be served by the DMA controller.

3.27 Serial Audio interface (SAI1)

The serial audio interface (SAI1) is based on two independent audio sub-blocks which can operate as transmitter or receiver with their FIFO. Many audio protocols are supported by each block: I2S standards, LSB or MSB-justified, PCM/DSP, TDM, AC'97 and SPDIF output, supporting audio sampling frequencies from 8 kHz up to 192 kHz. Both sub-blocks can be configured in master or in slave mode.

In master mode, the master clock can be output to the external DAC/CODEC at 256 times of the sampling frequency.

The two sub-blocks can be configured in synchronous mode when full-duplex mode is required.

SAI1 can be served by the DMA controller.

3.28 Audio PLL (PLLI2S)

The devices feature an additional dedicated PLL for audio I²S and SAI applications. It allows to achieve error-free I²S sampling clock accuracy without compromising on the CPU performance, while using USB peripherals.

Different sources can be selected for the I2S master clock of the APB1 and the I2S master clock of the APB2. This gives the flexibility to work with two different audio sampling frequencies. The different possible sources are the main PLL, the PLLI2S, HSE or HSI clocks or an external clock provided through a pin (external PLL or CODEC output)

Figure 17. STM32F413xG/H UFBGA144 pinout

	1	2	3	4	5	6	7	8	9	10	11	12
A	PC13	PE3	PE2	PE1	PE0	PB4	PB3	PD6	PD7	PA15	PA14	PA13
B	PC14- OSC32_IN	PE4	PE5	PE6	PB9	PB5	PG15	PG12	PD5	PC11	PC10	PA12
C	PC15- OSC32_OUT	VBAT	PF0	PF1	PB8	PB6	PG14	PG11	PD4	PC12	VDDUSB	PA11
D	PH0 - OSC_IN	VSS	VDD	PF2	BOOT0	PB7	PG13	PG10	PD3	PD1	PA10	PA9
E	PH1 - OSC_OUT	PF3	PF4	PF5	PDR_ON	VSS	VSS	PG9	PD2	PD0	PC9	PA8
F	NRST	PF7	PF6	VDD	VDD	VDD	VDD	VDD	VDD	VDD	PC8	PC7
G	PF10	PF9	PF8	VSS	VDD	VDD	VDD	VSS	VCAP_2	VSS	PG8	PC6
H	PC0	PC1	PC2	PC3	BYPASS_ REG	VSS	VCAP_1	PE11	PD11	PG7	PG6	PG5
J	VSSA	PA0	PA4	PC4	PB2	PG1	PE10	PE12	PD10	PG4	PG3	PG2
K	VREF-	PA1	PA5	PC5	PF13	PG0	PE9	PE13	PD9	PD13	PD14	PD15
L	VREF+	PA2	PA6	PB0	PF12	PF15	PE8	PE14	PD8	PD12	PB14	PB15
M	VDDA	PA3	PA7	PB1	PF11	PF14	PE7	PE15	PB10	PB11	PB12	PB13

MSv37283V2

1. The above figure shows the package top view.

Table 9. Legend/abbreviations used in the pinout table

Name	Abbreviation	Definition
Pin name	Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type	S	Supply pin
	I	Input only pin
	I/O	Input/ output pin
I/O structure	FT	5 V tolerant I/O
	FTf	5 V tolerant I/O, I2C FM+ option
	TC	Standard 3.3 V I/O
	TTa	3.3 V tolerant I/O directly connected to DAC
	B	Dedicated BOOT0 pin
	NRST	Bidirectional reset pin with embedded weak pull-up resistor
Notes	Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset	
Alternate functions	Functions selected through GPIOx_AFR registers	
Additional functions	Functions directly selected/enabled through peripheral registers	

Table 10. STM32F413xG/H pin definition (continued)

Pin Number							Pin name (function after reset) ⁽¹⁾	Pin type	I/O structure	Notes	Alternate functions	Additional functions
UFQFPN48	LQFP64	WLCSP81	LQFP100	UFBGA100	UFBGA144	LQFP144						
-	-	-	-	-	D8	125	PG10	I/O	FT	-	FSMC_NE3, EVENTOUT	-
-	-	-	-	-	C8	126	PG11	I/O	FT	-	CAN2_RX, UART10_RX, EVENTOUT	-
-	-	-	-	-	B8	127	PG12	I/O	FT	-	USART6_RTS, CAN2_TX, UART10_TX, FSMC_NE4, EVENTOUT	-
-	-	-	-	-	D7	128	PG13	I/O	FT	-	TRACED2, USART6_CTS, FSMC_A24, EVENTOUT	-
-	-	-	-	-	C7	129	PG14	I/O	FT	-	TRACED3, USART6_TX, QUADSPI_BK2_IO3, FSMC_A25, EVENTOUT	-
-	-	-	-	-	-	130	VSS	S	-	-	-	-
-	-	-	-	-	F6	131	VDD	S	-	-	-	-
-	-	-	-	-	B7	132	PG15	I/O	FT	-	USART6_CTS, EVENTOUT	-
39	55	A5	89	A8	A7	133	PB3	I/O	FTf	-	JTDO-SWO, TIM2_CH2, I2CFMP1_SDA, SPI1_SCK/I2S1_CK, SPI3_SCK/I2S3_CK, USART1_RX, UART7_RX, I2C2_SDA, SAI1_SD_A, CAN3_RX, EVENTOUT	-
40	56	B5	90	A7	A6	134	PB4	I/O	FT	-	JTRST, TIM3_CH1, SPI1_MISO, SPI3_MISO, I2S3ext_SD, UART7_TX, I2C3_SDA, SAI1_SCK_A, CAN3_TX, SDIO_D0, EVENTOUT	-

Table 11. FSMC pin definition (continued)

Pins	FSMC		64 pins	81 pins	100 pins	144 pins
	LCD/NOR/ PSRAM/SRAM	NOR/PSRAM Mux				
PA3	D5	DA5	Yes	Yes	Yes	Yes
PA4	D6	DA6	Yes	Yes	Yes	Yes
PA5	D7	DA7	Yes	Yes	Yes	Yes
PC4	NE4	NE4	Yes	Yes	Yes	Yes
PC5	NOE	NOE	Yes	Yes	Yes	Yes
PF12	A6	-	-	-	-	Yes
PF13	A7	-	-	-	-	Yes
PF14	A8	-	-	-	-	Yes
PF15	A9	-	-	-	-	Yes
PG0	A10	-	-	-	-	Yes
PG1	A11	-	-	-	-	Yes
PE7	D4	DA4	-	-	Yes	Yes
PE8	D5	DA5	-	-	Yes	Yes
PE9	D6	DA6	-	Yes	Yes	Yes
PE10	D7	DA7	-	Yes	Yes	Yes
PE11	D8	DA8	-	Yes	Yes	Yes
PE12	D9	DA9	-	Yes	Yes	Yes
PE13	D10	DA10	-	Yes	Yes	Yes
PE14	D11	DA11	-	Yes	Yes	Yes
PE15	D12	DA12	-	Yes	Yes	Yes
PB12	D13	DA13	Yes	Yes	Yes	Yes
PB14	D0	DA0	Yes	Yes	Yes	Yes
PD8	D13	DA13	-	-	-	Yes
PD9	D14	DA14	-	Yes	Yes	Yes
PD10	D15	DA15	-	Yes	Yes	Yes
PD11	A16	A16	-	-	Yes	Yes
PD12	A17	A17	-	-	Yes	Yes
PD13	A18	A18	-	-	Yes	Yes
PD14	D0	DA0	-	-	Yes	Yes
PD15	D1	DA1	-	-	Yes	Yes
PG2	A12	-	-	-	-	Yes
PG3	A13	-	-	-	-	Yes
PG4	A14	-	-	-	-	Yes



Table 12. STM32F413xG/H alternate functions

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM1/2/ LPTIM1	TIM3/4/5	DFSDM2/ TIM8/9/10/11	I2C1/2/3/ I2CFMP1	SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4	SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4/ SPI5/I2S5/ DFSDM1/2	SPI3/I2S3/ SAI1/ DFSDM2/ USART1/ USART2/ USART3	DFSDM1/ USART3/4/ 5/6/7/8/ CAN1	I2C2/I2C3/ I2CFMP1/ CAN1/2/ TIM12/13/14/ QUADSPI	SAI1/ DFSDM1/ DFSDM2/ QUADSPI/ FSMC /OTG1_FS	UART4/ UART5/ UART9/ UART10 /CAN3	FSMC /SDIO	-	RNG	SYS_AF
Port A	PA0	-	TIM2_CH1 /TIM2_ETR	TIM5_CH1	TIM8_ETR	-	-	-	USART2_CTS	UART4_TX	-	-	-	-	-	EVENT OUT
	PA1	-	TIM2_CH2	TIM5_CH2	-	-	SPI4_MOSI/ I2S4_SD	-	USART2_RTS	UART4_RX	QUADSPI_BK1_IO3	-	-	-	-	EVENT OUT
	PA2	-	TIM2_CH3	TIM5_CH3	TIM9_CH1	-	I2S2_CKIN	-	USART2_TX	-	-	-	FSMC_D4/ FSMC_DA4	-	-	EVENT OUT
	PA3	-	TIM2_CH4	TIM5_CH4	TIM9_CH2	-	I2S2_MCK	-	USART2_RX	-	-	SAI1_SD_B	FSMC_D5/ FSMC_DA5	-	-	EVENT OUT
	PA4	-	-	-	-	-	SPI1_NSS/ I2S1_WS	SPI3_NSS/ I2S3_WS	USART2_CK	DFSDM1_DATIN1	-	-	FSMC_D6/ FSMC_DA6	-	-	EVENT OUT
	PA5	-	TIM2_CH1 /TIM2_ETR	-	TIM8_CH1N	-	SPI1_SCK/ I2S1_CK	-	-	DFSDM1_CKIN1	-	-	FSMC_D7/ FSMC_DA7	-	-	EVENT OUT
	PA6	-	TIM1_BKIN	TIM3_CH1	TIM8_BKIN	-	SPI1_MISO	I2S2_MCK	DFSDM2_CKIN1	-	TIM13_CH1	QUADSPI_BK2_IO0	SDIO_CMD	-	-	EVENT OUT
	PA7	-	TIM1_CH1N	TIM3_CH2	TIM8_CH1N	-	SPI1_MOSI/ I2S1_SD	-	DFSDM2_DATIN1	-	TIM14_CH1	QUADSPI_BK2_IO1	-	-	-	EVENT OUT
	PA8	MCO_1	TIM1_CH1	-	-	I2C3_SCL	-	DFSDM1_CKOUT	USART1_CK	UART7_RX	-	USB_FS_SOF	CAN3_RX	SDIO_D1	-	EVENT OUT
	PA9	-	TIM1_CH2	-	DFSDM2_CKIN3	I2C3_SMBA	SPI2_SCK/ I2S2_CK	-	USART1_TX	-	-	USB_FS_VBUS	-	SDIO_D2	-	EVENT OUT
	PA10	-	TIM1_CH3	-	DFSDM2_DATIN3	-	SPI2_MOSI/ I2S2_SD	SPI5_MOSI/ I2S5_SD	USART1_RX	-	-	USB_FS_ID	-	-	-	EVENT OUT
	PA11	-	TIM1_CH4	-	DFSDM2_CKIN5	-	SPI2_NSS/ I2S2_WS	SPI4_MISO	USART1_CTS	USART6_TX	CAN1_RX	USB_FS_DM	UART4_RX	-	-	EVENT OUT
	PA12	-	TIM1_ETR	-	DFSDM2_DATIN5	-	SPI2_MISO	SPI5_MISO	USART1_RTS	USART6_RX	CAN1_TX	USB_FS_DP	UART4_TX	-	-	EVENT OUT
	PA13	JTMS-SWDIO	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PA14	JTCK-SWCLK	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PA15	JTDI	TIM2_CH1 /TIM2_ETR	-	-	-	SPI1_NSS/ I2S1_WS	SPI3_NSS/ I2S3_WS	USART1_TX	UART7_TX	-	SAI1_MCLK_A	CAN3_TX	-	-	EVENT OUT



Table 12. STM32F413xG/H alternate functions (continued)

Port	AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM1/2/ LPTIM1	TIM3/4/5	DFSDM2/ TIM8/9/10/11	I2C1/2/3/ I2CFMP1	SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4	SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4/ SPI5/I2S5/ DFSDM1/2	SPI3/I2S3/ SAI1/ DFSDM2/ USART1/ USART2/ USART3	DFSDM1/ USART3/4/ 5/6/7/8/ CAN1	I2C2/I2C3/ I2CFMP1/ CAN1/2/ TIM12/13/14/ QUADSPI	SAI1/ DFSDM1/ DFSDM2/ QUADSPI/ FSMC /OTG1_FS	UART4/ UART5/ UART9/ UART10 /CAN3	FSMC /SDIO	-	RNG	SYS_AF
Port C	PC0	-	LPTIM1_IN1	-	DFSDM2_C KIN4	-	-	SAI1_MCL K_B	-	-	-	-	-	-	-	EVENT OUT
	PC1	-	LPTIM1_OUT	-	DFSDM2_D ATIN4	-	-	SAI1_SD_B	-	-	-	-	-	-	-	EVENT OUT
	PC2	-	LPTIM1_I N2	-	DFSDM2_D ATIN7	-	SPI2_MISO	I2S2ext_SD	SAI1_SCK_B	DFSDM1 CKOUT	-	-	-	FSMC_NWE	-	EVENT OUT
	PC3	-	LPTIM1_ETR	-	DFSDM2_C KIN7	-	SPI2_MOSI/ I2S2_SD	-	SAI1_FS_B	-	-	-	-	FSMC_A0	-	EVENT OUT
	PC4	-	-	-	DFSDM2_C KIN2	-	I2S1_MCK	-	-	-	-	QUADSPI_ BK2_IO2	-	FSMC_NE4	-	EVENT OUT
	PC5	-	-	-	DFSDM2_D ATIN2	I2CFMP1 _SMBA	-	-	USART3_R X	-	-	QUADSPI_ BK2_IO3	-	FSMC_NOE	-	EVENT OUT
	PC6	-	-	TIM3_ CH1	TIM8_CH1	I2CFMP1 _SCL	I2S2_MCK	DFSDM1_ CKIN3	DFSDM2_ DATIN6	USART6_ TX	-	FSMC_D1/ FSMC_DA1	-	SDIO_D6	-	EVENT OUT
	PC7	-	-	TIM3_ CH2	TIM8_CH2	I2CFMP1 _SDA	SPI2_SCK/ I2S2_CK	I2S3_MCK	DFSDM2_ CKIN6	USART6_ RX	-	DFSDM1_D ATIN3	-	SDIO_D7	-	EVENT OUT
	PC8	-	-	TIM3_ CH3	TIM8_CH3	-	-	-	DFSDM2_ CKIN3	USART6_ CK	QUADSPI_ BK1_IO2	-	-	SDIO_D0	-	EVENT OUT
	PC9	MCO_2	-	TIM3_ CH4	TIM8_CH4	I2C3_ SDA	I2S2_CKIN	-	DFSDM2_ DATIN3	-	QUADSPI_ BK1_IO0	-	-	SDIO_D1	-	EVENT OUT
	PC10	-	-	-	DFSDM2_ CKIN5	-	-	SPI3_SCK/ I2S3_CK	USART3_ TX	-	QUADSPI_ BK1_IO1	-	-	SDIO_D2	-	EVENT OUT
	PC11	-	-	-	DFSDM2_ DATIN5	-	I2S3ext_SD	SPI3_MISO	USART3_ RX	UART4_ RX	QUADSPI_ BK2_NCS	FSMC_D2/ FSMC_DA2	-	SDIO_D3	-	EVENT OUT
	PC12	-	-	-	-	-	-	SPI3_MOSI/ I2S3_SD	USART3_ CK	UART5_ TX	-	FSMC_D3/ FSMC_DA3	-	SDIO_CK	-	EVENT OUT
	PC13	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PC14	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PC15	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT

Table 12. STM32F413xG/H alternate functions (continued)

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM1/2/ LPTIM1	TIM3/4/5	DFSDM2/ TIM8/9/10/11	I2C1/2/3/ I2CFMP1	SPI1/I2S1/ SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4	SPI2/I2S2/ SPI3/I2S3/ SPI4/I2S4/ SPI5/I2S5/ DFSDM1/2	SPI3/I2S3/ SAI1/ DFSDM2/ USART1/ USART2/ USART3	DFSDM1/ USART3/4/ 5/6/7/8/ CAN1	I2C2/I2C3/ I2CFMP1/ CAN1/2/ TIM12/13/14/ QUADSPI	SAI1/ DFSDM1/ DFSDM2/ QUADSPI/ FSMC /OTG1_FS	UART4/ UART5/ UART9/ UART10 /CAN3	FSMC /SDIO	-	RNG	SYS_AF
PortH	PH0	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PH1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT

Table 27. Typical and maximum current consumption in run mode, code with data processing (ART accelerator disabled) running from Flash memory - $V_{DD} = 3.6\text{ V}$

Symbol	Parameter	Conditions	f _{HCLK} (MHz)	Typ	Max ⁽¹⁾					Unit
				T _A = 25 °C	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	T _A = 125 °C		
I _{DD}	Supply current in Run mode	External clock, PLL ON ⁽²⁾ , all peripherals enabled ⁽³⁾	100	39.9	42.46	43.17	45.32	49.19	mA	
			84	32.6	34.71	35.45	37.58	41.24		
			64	24.2	25.86	26.73	28.47	31.96		
			50	19.7	21.01	22.00	23.74	27.26		
			25	10.8	11.55	12.83	14.66	18.03		
			20	9.2	9.82	11.16	13.09	16.36		
		HSI, PLL OFF, all peripherals enabled ⁽³⁾	16	6.8	7.33	8.77	10.69	14.00		
			1	1.2	1.83	3.08	4.83	8.19		
		External clock, PLL ON ⁽²⁾ , all peripherals disabled ⁽³⁾	100	22.3	24.11	25.26	27.35	31.11		
			84	18.5	20.00	21.15	23.20	26.87		
			64	14.6	15.81	17.02	18.74	22.20		
			50	12.2	13.14	14.45	16.18	19.66		
			25	7.0	7.52	8.95	10.84	14.19		
			20	6.0	6.58	7.95	9.74	13.07		
		HSI, PLL OFF, all peripherals disabled ⁽³⁾	16	4.5	4.97	6.40	8.30	11.59		
			1	1.0	1.61	2.94	4.65	8.05		

1. Guaranteed by characterization results.

2. Refer to [Table 47](#) and RM0383 for the possible PLL VCO setting

3. Add an additional power consumption of 1.6 mA per ADC for the analog part. In applications, this consumption occurs only while the ADC is ON (ADON bit is set in the ADC_CR2 register).

Table 39. Peripheral current consumption (continued)

Peripheral		I _{DD} (Typ)			Unit
		Scale 1	Scale 2	Scale 3	
APB2	AHB-APB2 bridge	0.10	0.11	0.09	μA/MHz
	TIM1	6.78	6.46	5.80	
	TIM8	6.94	6.62	5.94	
	USART1	3.14	3.00	2.69	
	USART6	3.12	2.98	2.67	
	UART9	2.89	1.98	1.75	
	UART10	2.91	2.00	1.77	
	ADC1	3.45	3.29	2.95	
	SDIO	3.54	3.37	3.03	
	SPI1	1.52	1.46	1.31	
	SPI4	1.50	1.43	1.28	
	SYSCFG	0.58	0.55	0.50	
	EXT1	0.91	0.86	0.78	
	TIM9	2.95	2.81	2.53	
	TIM10	1.88	1.79	1.61	
	TIM11	1.86	1.77	1.59	
	SPI5	1.50	1.43	1.30	
	SAI	2.89	2.75	2.47	
	DFSDM1	4.43	4.21	3.80	
	DFSDM2	7.08	6.76	6.05	
Bus Matrix		4.06	3.87	3.45	

1. N is the number of stream enable (1...8).

6.3.7 Wakeup time from low-power modes

The wakeup times given in [Table 40](#) are measured starting from the wakeup event trigger up to the first instruction executed by the CPU:

- For Stop or Sleep modes: the wakeup event is WFE.
- WKUP (PA0/PC0/PC1) pins are used to wakeup from Standby, Stop and Sleep modes.

The characteristics given in [Table 41](#) result from tests performed using an high-speed external clock source, and under ambient temperature and supply voltage conditions summarized in [Table 17](#).

Table 41. High-speed external user clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	External user clock source frequency ⁽¹⁾		1	-	50	MHz
V_{HSEH}	OSC_IN input pin high level voltage		$0.7V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(HSE)}$ $t_{f(HSE)}$	OSC_IN high or low time ⁽¹⁾		5	-	-	ns
$t_{r(HSE)}$ $t_{f(HSE)}$	OSC_IN rise or fall time ⁽¹⁾		-	-	10	
$C_{in(HSE)}$	OSC_IN input capacitance ⁽¹⁾		-	5	-	pF
$DuCy_{(HSE)}$	Duty cycle		45	-	55	%
I_L	OSC_IN Input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	± 1	μA

1. Guaranteed by design.

Low-speed external user clock generated from an external source

In bypass mode the LSE oscillator is switched off and the input pin is a standard I/O. The external clock signal has to respect the [Table 59](#). However, the recommended clock input waveform is shown in [Figure 28](#).

The characteristics given in [Table 42](#) result from tests performed using an low-speed external clock source, and under ambient temperature and supply voltage conditions summarized in [Table 17](#).

Table 42. Low-speed external user clock characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{LSE_ext}	User External clock source frequency ⁽¹⁾		-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high level voltage		$0.7V_{DD}$	-	V_{DD}	V
V_{LSEL}	OSC32_IN input pin low level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(LSE)}$ $t_{f(LSE)}$	OSC32_IN high or low time ⁽¹⁾		450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time ⁽¹⁾		-	-	50	
$C_{in(LSE)}$	OSC32_IN input capacitance ⁽¹⁾		-	5	-	pF
$DuCy_{(LSE)}$	Duty cycle		30	-	70	%
I_L	OSC32_IN Input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	± 1	μA

1. Guaranteed by design.

6.3.9 Internal clock source characteristics

The parameters given in [Table 45](#) and [Table 46](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 17](#).

High-speed internal (HSI) RC oscillator

Table 45. HSI oscillator characteristics ⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency	-	-	16	-	MHz
ACC_{HSI}	HSI user trimming step ⁽²⁾	-	-	-	1	%
	Accuracy of the HSI oscillator	$T_A = -40$ to 125 °C ⁽³⁾	-8	-	6.75	%
		$T_A = -40$ to 105 °C ⁽³⁾	-8	-	4.5	%
		$T_A = -10$ to 85 °C ⁽³⁾	-4	-	4	%
		$T_A = 25$ °C ⁽⁴⁾	-1	-	1	%
$t_{su(HSI)}$ ⁽²⁾	HSI oscillator startup time	-	-	2.2	4	μs
$I_{DD(HSI)}$ ⁽²⁾	HSI oscillator power consumption	-	-	60	80	μA

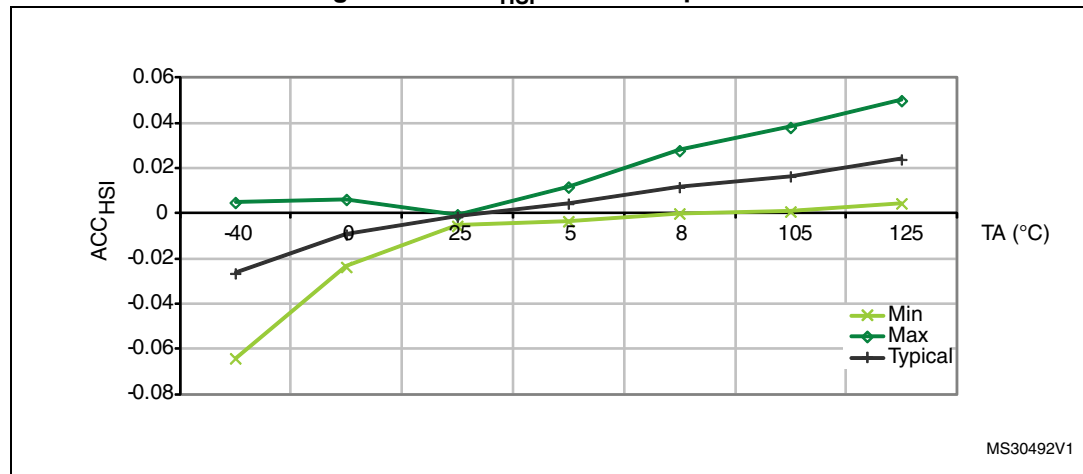
1. $V_{DD} = 3.3$ V, $T_A = -40$ to 125 °C unless otherwise specified.

2. Guaranteed by design

3. Based on characterization

4. Factory calibrated, parts not soldered.

Figure 31. ACC_{HSI} versus temperature



1. Guaranteed by characterization results.

Table 56. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value ⁽¹⁾	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	$T_A = +25\text{ °C}$ conforming to JESD22-A114	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	$T_A = +25\text{ °C}$ conforming to ANSI/ESD STM5.3.1, UFBGA144, UFBGA100, LQFP144, LQFP100, WLCSP81, LQFP64	3	250	
		$T_A = +25\text{ °C}$ conforming to ANSI/ESD STM5.3.1, UFQFPN48	4	500	

1. Guaranteed by characterization results.

Static latchup

Two complementary static tests are required on six parts to assess the latchup performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latchup standard.

Table 57. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	$T_A = +125\text{ °C}$ conforming to JESD78A	II level A

6.3.15 I/O current injection characteristics

As a general rule, current injection to the I/O pins, due to external voltage below V_{SS} or above V_{DD} (for standard, 3 V-capable I/O pins) should be avoided during normal product operation. However, in order to give an indication of the robustness of the microcontroller in cases when abnormal injection accidentally happens, susceptibility tests are performed on a sample basis during device characterization.

Functional susceptibility to I/O current injection

While a simple application is executed on the device, the device is stressed by injecting current into the I/O pins programmed in floating input mode. While current is injected into the I/O pin, one at a time, the device is checked for functional failures.

The failure is indicated by an out of range parameter: ADC error above a certain limit (>5 LSB TUE), out of conventional limits of induced leakage current on adjacent pins (out of $-5\text{ }\mu\text{A}/+0\text{ }\mu\text{A}$ range), or other functional failure (for example reset, oscillator frequency deviation).

Negative induced leakage current is caused by negative injection and positive induced leakage current by positive injection.

The test results are given in [Table 58](#).

Table 59. I/O static characteristics (continued)

Symbol	Parameter		Conditions	Min	Typ	Max	Unit
I_{lkg}	I/O input leakage current ⁽⁴⁾		$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	± 1	μA
	I/O FT/TC input leakage current ⁽⁵⁾		$V_{IN} = 5 V$	-	-	3	
R_{PU}	Weak pull-up equivalent resistor ⁽⁶⁾	All pins except for PA10 (OTG_FS_ID)	$V_{IN} = V_{SS}$	30	40	50	$k\Omega$
		PA10 (OTG_FS_ID)	-	7	10	14	
R_{PD}	Weak pull-down equivalent resistor ⁽⁷⁾	All pins except for PA10 (OTG_FS_ID)	$V_{IN} = V_{DD}$	30	40	50	
		PA10 (OTG_FS_ID)	-	7	10	14	
$C_{IO}^{(8)}$	I/O pin capacitance		-	-	5	-	pF

1. Guaranteed by test in production.
2. Guaranteed by design.
3. With a minimum of 200 mV.
4. Leakage could be higher than the maximum value, if negative current is injected on adjacent pins, Refer to [Table 58: I/O current injection susceptibility](#)
5. To sustain a voltage higher than $V_{DD} + 0.3 V$, the internal pull-up/pull-down resistors must be disabled. Leakage could be higher than the maximum value, if negative current is injected on adjacent pins. Refer to [Table 58: I/O current injection susceptibility](#)
6. Pull-up resistors are designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is minimum (~10% order).
7. Pull-down resistors are designed with a true resistance in series with a switchable NMOS. This NMOS contribution to the series resistance is minimum (~10% order).
8. Hysteresis voltage between Schmitt trigger switching levels. Guaranteed by characterization results.

All I/Os are CMOS and TTL compliant (no software configuration required). Their characteristics cover more than the strict CMOS-technology or TTL parameters. The coverage of these requirements for FT and TC I/Os is shown in [Figure 35](#).

6.3.19 Communications interfaces

I²C interface characteristics

The I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but is still present.

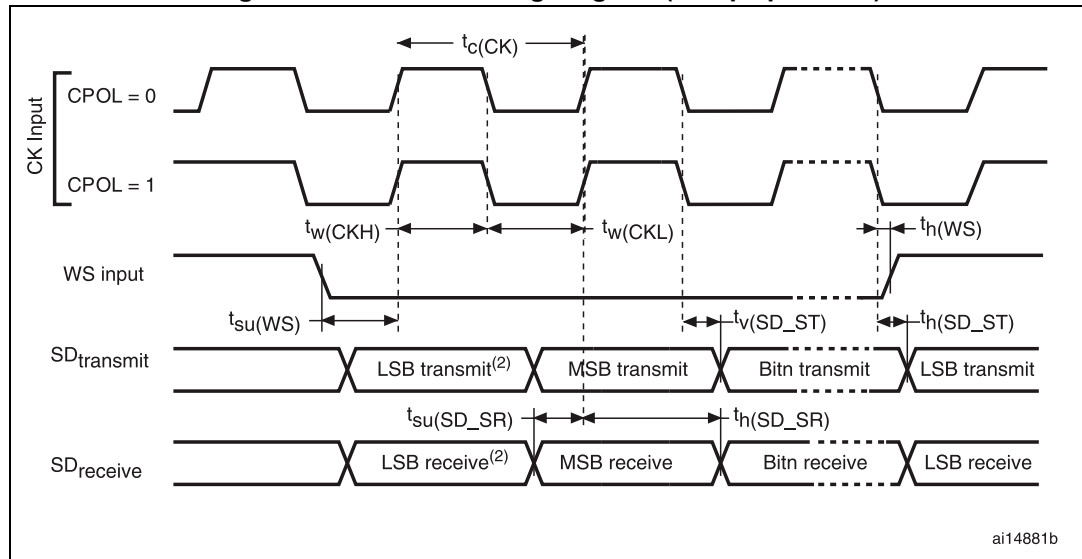
The I²C characteristics are described in [Table 64](#). Refer also to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

The I²C bus interface supports standard mode (up to 100 kHz) and fast mode (up to 400 kHz). The I²C bus frequency can be increased up to 1 MHz. For more details about the complete solution, contact your local ST sales representative.

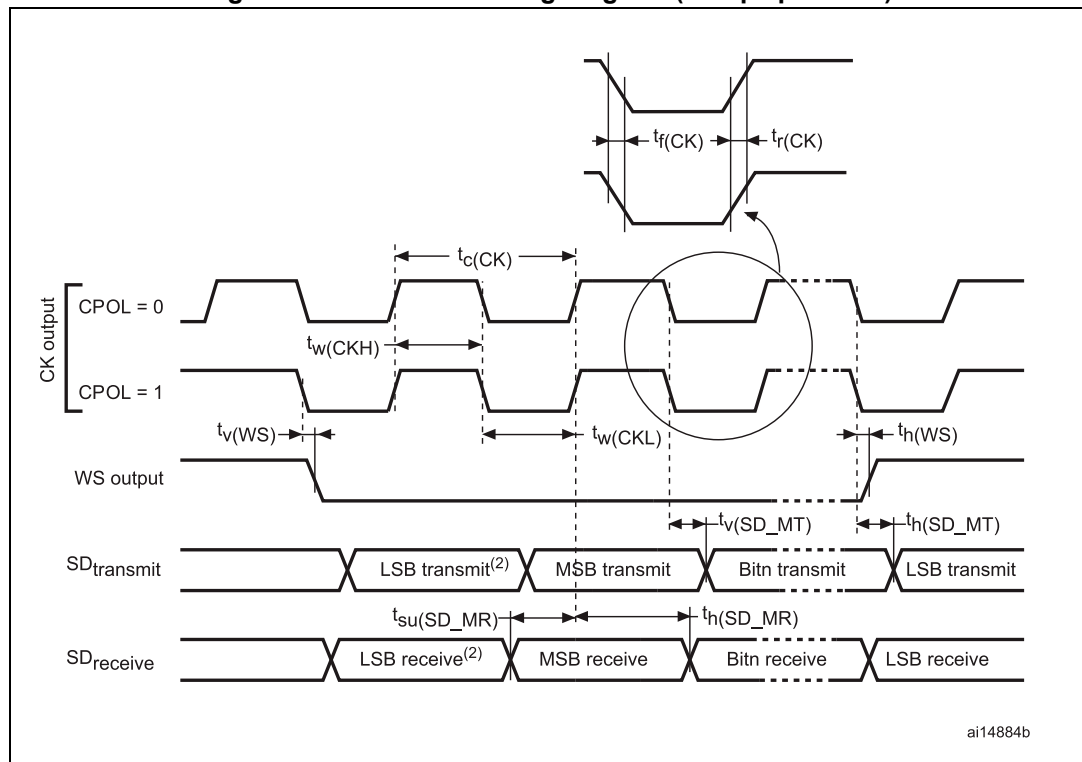
Table 64. I²C characteristics

Symbol	Parameter	Standard mode I ² C ⁽¹⁾⁽²⁾		Fast mode I ² C ⁽¹⁾⁽²⁾		Unit
		Min	Max	Min	Max	
t _{w(SCLL)}	SCL clock low time	4.70	-	1.30	-	μs
t _{w(SCLH)}	SCL clock high time	4.0	-	0.60	-	
t _{su(SDA)}	SDA setup time	0.25	-	0.10	-	
t _{h(SDA)}	SDA data hold time	0	-	0	-	
t _{v(SDA,ACK)}	SDA data hold time	-	3.45 ⁽³⁾	-	0.90 ⁽⁴⁾	
t _{r(SDA)} t _{r(SCL)}	SDA and SCL rise time	-	0.100	-	0.30	
t _{f(SDA)} t _{f(SCL)}	SDA and SCL fall time	-	0.30	-	0.30	
t _{h(STA)}	Start condition hold time	4	-	0.6	-	
t _{su(STA)}	Repeated Start condition setup time	4.7	-	0.6	-	
t _{su(STO)}	Stop condition setup time	4	-	0.60	-	
t _{w(STO:STA)}	Stop to Start condition time (bus free)	4.70	-	1.3	-	
t _{SP}	Pulse width of the spikes that are suppressed by the analog filter for standard fast mode	-	-	0.05	0.10 ⁽⁵⁾	
C _b	Capacitive load for each bus line	-	400	-	400	pF

1. Guaranteed by design.
2. f_{PCLK1} must be at least 2 MHz to achieve standard mode I²C frequencies. It must be at least 4 MHz to achieve fast mode I²C frequencies, and a multiple of 10 MHz to reach the 400 kHz maximum I²C fast mode clock.
3. The device must internally provide a hold time of at least 300 ns for the SDA signal in order to bridge the undefined region of the falling edge of SCL.
4. The maximum data hold time has only to be met if the interface does not stretch the low period of SCL signal.
5. The minimum width of the spikes filtered by the analog filter is above t_{SP} (max)

Figure 43. I²S slave timing diagram (Philips protocol)

1. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

Figure 44. I²S master timing diagram (Philips protocol)

1. LSB transmit/receive of the previously transmitted byte. No LSB transmit/receive is sent before the first byte.

6.3.26 FSMC characteristics

Unless otherwise specified, the parameters given in [Table 88](#) to [Table 95](#) for the FSMC interface are derived from tests performed under the ambient temperature, f_{HCLK} frequency and V_{DD} supply voltage conditions summarized in [Table 16](#), with the following configuration:

- Output speed is set to $\text{OSPEEDRy}[1:0] = 10$
- Capacitance load $C = 30 \text{ pF}$
- Measurement points are done at CMOS levels: $0.5 \cdot V_{\text{DD}}$

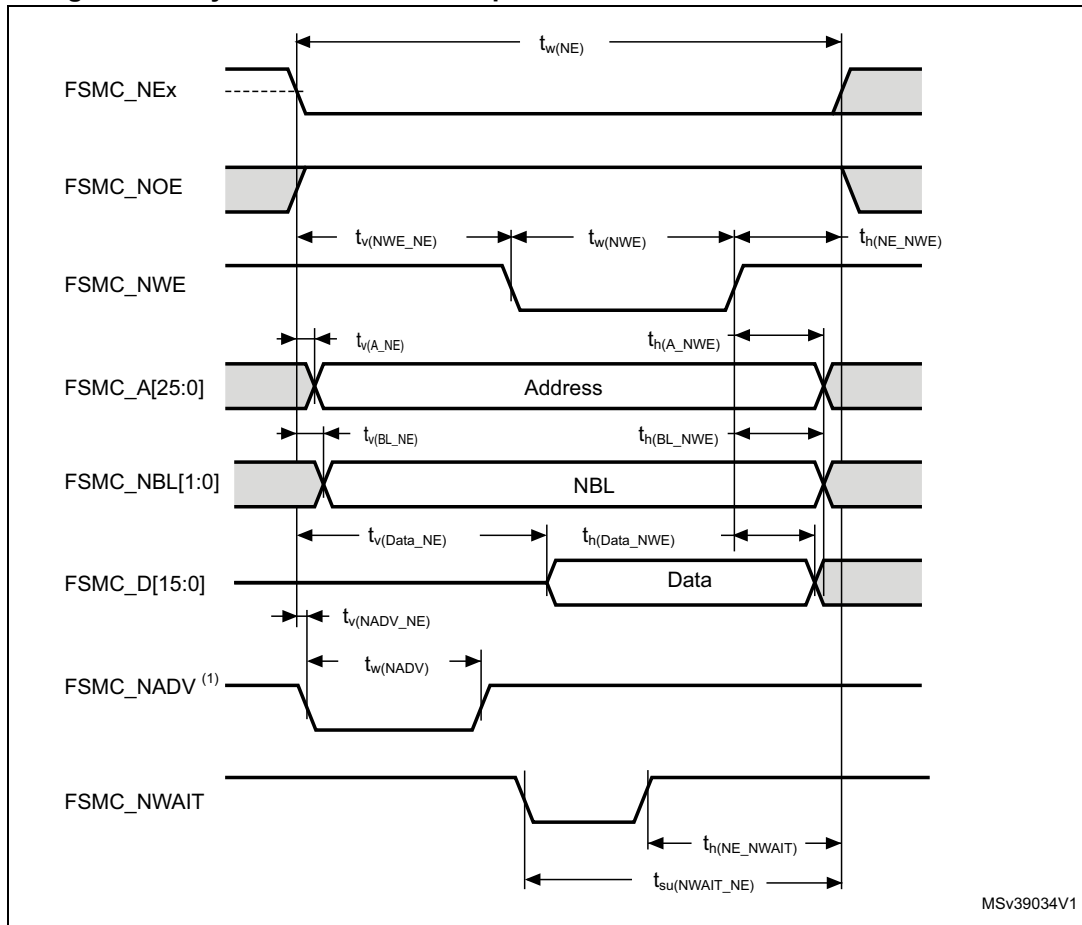
Refer to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output characteristics.

Asynchronous waveforms and timings

[Figure 53](#) through [Figure 56](#) represent asynchronous waveforms and [Table 88](#) through [Table 95](#) provide the corresponding timings. The results shown in these tables are obtained with the following FSMC configuration:

- $\text{AddressSetupTime} = 0x1$
- $\text{AddressHoldTime} = 0x1$
- $\text{DataSetupTime} = 0x1$ (except for asynchronous NWAIT mode, $\text{DataSetupTime} = 0x5$)
- $\text{BusTurnAroundDuration} = 0x0$

In all timing tables, the T_{HCLK} is the HCLK clock period.

Figure 54. Asynchronous non-multiplexed SRAM/PSRAM/NOR write waveforms

1. Mode 2/B, C and D only. In Mode 1, FSMC_NADV is not used.

Table 90. Asynchronous non-multiplexed SRAM/PSRAM/NOR write timings⁽¹⁾⁽²⁾

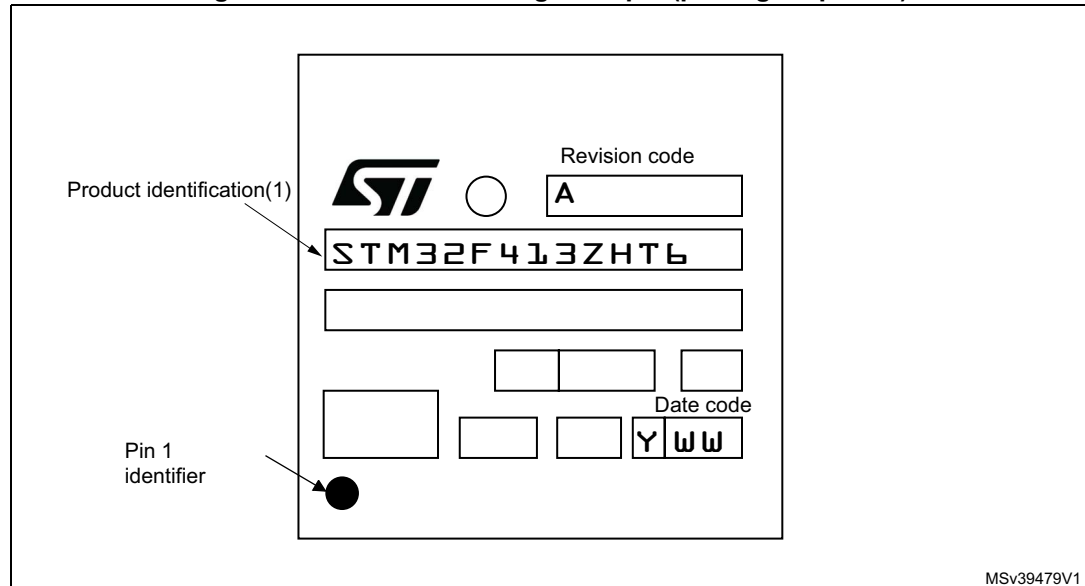
Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FSMC_NEx low time	$3 * t_{HCLK} - 1$	$3 * t_{HCLK} - 1$	ns
$t_{v(NWE_NE)}$	FSMC_NEx low to FSMC_NWE low	$t_{HCLK} - 1$	$t_{HCLK} + 0.5$	
$t_{w(NWE)}$	FSMC_NWE low time	$t_{HCLK} - 1.5$	$t_{HCLK} + 0.5$	
$t_{h(NE_NWE)}$	FSMC_NWE high to FSMC_NEx high hold time	t_{HCLK}	-	
$t_{v(A_NE)}$	FSMC_NEx low to FSMC_A valid	-	0	
$t_{h(A_NWE)}$	Address hold time after FSMC_NWE high	$t_{HCLK} - 0.5$	-	
$t_{v(BL_NE)}$	FSMC_NEx low to FSMC_NBL valid	-	0.5	
$t_{h(BL_NWE)}$	FSMC_NBL hold time after FSMC_NWE high	$t_{HCLK} - 0.5$	-	
$t_{v(Data_NE)}$	Data to FSMC_NEx low to Data valid	-	$t_{HCLK} + 2.5$	
$t_{h(Data_NWE)}$	Data hold time after FSMC_NWE high	t_{HCLK}	-	
$t_{v(NADV_NE)}$	FSMC_NEx low to FSMC_NADV low	-	0	
$t_{w(NADV)}$	FSMC_NADV low time	-	$t_{HCLK} + 1$	

Device marking for LQFP144

The following figure gives an example of topside marking and pin 1 position identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 77. LQFP144 marking example (package top view)



1. Parts marked as “ES”, “E” or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

7.7 UFBGA144 package information

Figure 81. UFBGA144 - 144-pin, 10 x 10 mm, 0.80 mm pitch, ultra fine pitch ball grid array package outline

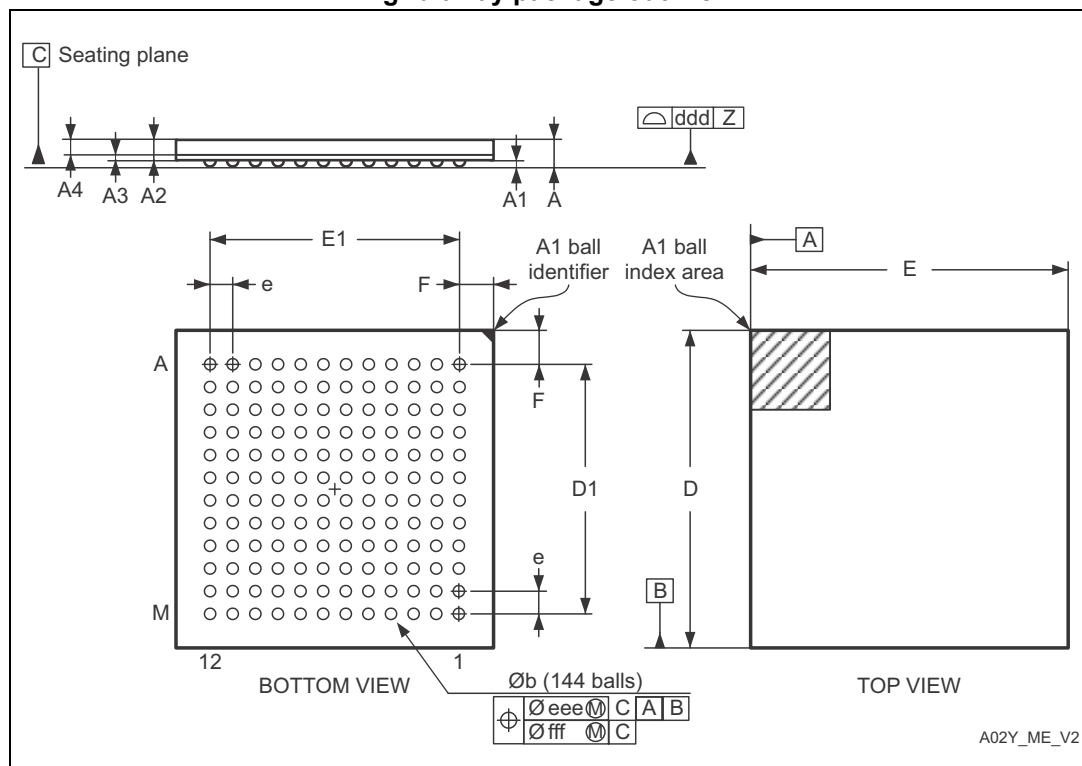


Table 111. UFBGA144 - 144-ball, 10 x 10 mm, 0.80 mm pitch, ultra fine pitch ball grid array package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	-	0.130	-	-	0.0051	-
A4	-	0.320	-	-	0.0126	-
b	0.360	0.400	0.440	0.0091	0.0110	0.0130
D	9.950	10.000	10.050	0.2736	0.2756	0.2776
D1	8.750	8.800	8.850	0.2343	0.2362	0.2382
E	9.950	10.000	10.050	0.2736	0.2756	0.2776
E1	8.750	8.800	8.850	0.2343	0.2362	0.2382
e	0.750	0.800	0.850	-	0.0197	-